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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/010,719	MAO ET AL.	
Examiner	Art Unit	
Jade O. Laye	2617	

SEARCHED			
Class	Subclass	Date	Examiner
725	93 103	12/15/2005	JL

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
consulted with Scott Believau	12/15/2005	JL
US databases only		
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